

<b>Notice of References Cited</b>	Application/Control No. 10/015,433	Applicant(s)/Patent Under Reexamination KRANZ ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,451,181	09-2002	Denning et al.	204/192.17
	B	US-6,132,813	10-2000	Chen et al.	427/490
	C	US-6,107,192	08-2000	Subrahmanyam et al.	438/637
	D	US-6,033,482	03-2000	Parkhe, Vijay	118/728
	E	US-5,236,537	08-1993	Asaka, Tatsuya	156/345.31
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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